

DATA SHEET		Date	Apr.01,2002
Model	CBS2002428	Temp.	25 °C
Test	Static electricity immunity test 静電気放電試験	Humid.	40 %Rh
		Tested by	T.Oiwake

- Method — according to EN61000-4-2 —
 - Points to be applied voltage
電圧印加箇所
Input pin / Output pin / Case pin / RC pin / TRM pin
入力ピン / 出力ピン / ケースピン / RCピン / TRMピン
 - Testing shall be satisfied at the lower levels given below
印加電圧はレベル1から4まで順次実施(下表参照)
 - Change the polarity (+/-) of applied voltage
印加極性 +/- の条件でそれぞれ実施
 - For the time interval between successive single discharges an initial value of 1s. is recommended.
On preselected points at least ten single discharges shall be applied.
1秒以上の間隔で各ポイント10回実施
 - Contact discharge method
接触放電で実施

Test levels of EN61000-4-2

Level	1	2	3	4
Contact discharge [kV]	2	4	6	8
Air discharge [kV]	2	4	8	15

- Conditions
 - Input : DC24V
 - Output : Rated output
 - Ambient temp. : 25±10°C
- Conditions of Acceptability

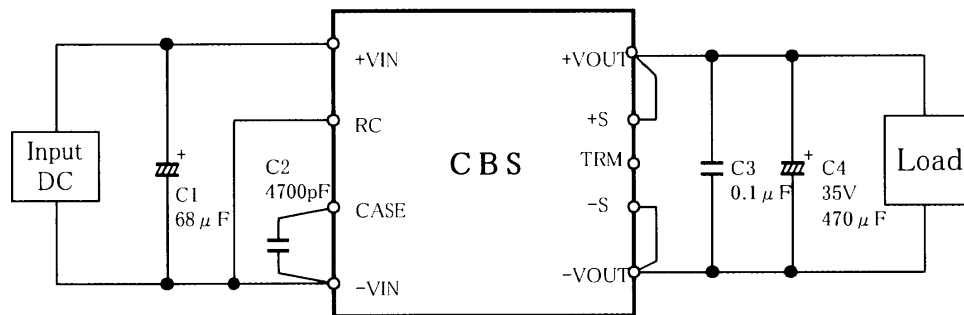
According to EN50082-2 (EN61000-4-2 Level 2)
EN50082-2(EN61000-4-2 レベル2)を満足すること

4. Result

No.	Level	Voltage [kV]	Polarity	Pin to be tested						
				+VIN	-VIN	+VOUT,+S	-VOUT,-S	CASE	RC	TRM
1	1	2	+	OK	OK	OK	OK	OK	OK	OK
2			-	OK	OK	OK	OK	OK	OK	OK
3	2	4	+	OK	OK	OK	OK	OK	OK	OK
4			-	OK	OK	OK	OK	OK	OK	OK
5	3	6	+	OK	OK	OK	OK	OK	OK	OK
6			-	OK	OK	OK	OK	OK	OK	OK
7	4	8	+	OK	OK	OK	OK	OK	OK	OK
8			-	OK	OK	OK	OK	OK	OK	OK

All are satisfactory to item 3: OK

5. Testing circuitry



C1: 50V68 μ F PMseries(nichicon)
 C2: DE1307-640E472M-KH(MURATA)
 C3: MDD21H104M(Nitsuko)
 C4: 35V470 μ F LXZseries(NIPPON CHEMI-CON)

Fig. Testing circuitry

DATA SHEET		Date	Apr.17,2002
Model	CBS2002428	Temp.	25 °C
Test	Radiated, radio-frequency, electromagnetic field immunity test 放射無線周波電磁界イミュニティ試験	Humid.	40 %Rh
		Tested by	T.Oiwake

1. Method — according to EN61000-4-3 —

These tests are defined for measuring the effect that electromagnetic radiation has on the equipment connected. The tests shall be made in a shielded enclosure.

対象機器に対する電磁放射の影響を測定する。試験はシールドルームで行われること。

- (1) Frequency band : 80MHz to 1000MHz
周波数範囲 : 80MHz から 1000MHz

- (2) Test levels
試験レベル

Test levels of EN61000-4-3

Level	Testing field strength V/m
1	1
2	3
3	10

2. Conditions

- (1) Input : DC24V
(2) Output : Rated output
(3) Ambient temp. : $25 \pm 10^{\circ}\text{C}$
(4) Testing circuitry : Fig.1

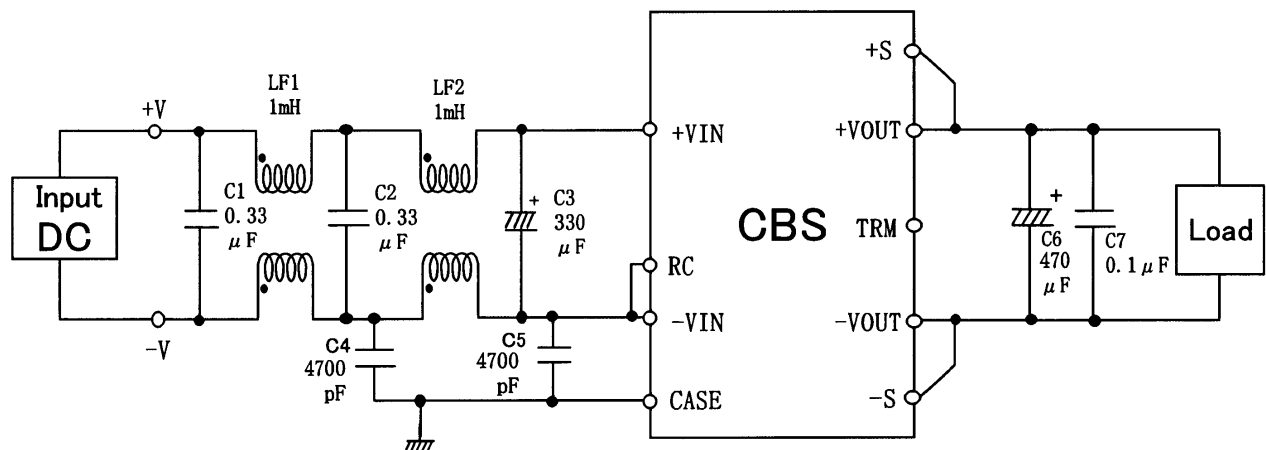


Fig.1 Testing circuitry

3. Conditions of Acceptability

According to EN61000-4-3 Level3
EN61000-4-3 レベル3を満足すること

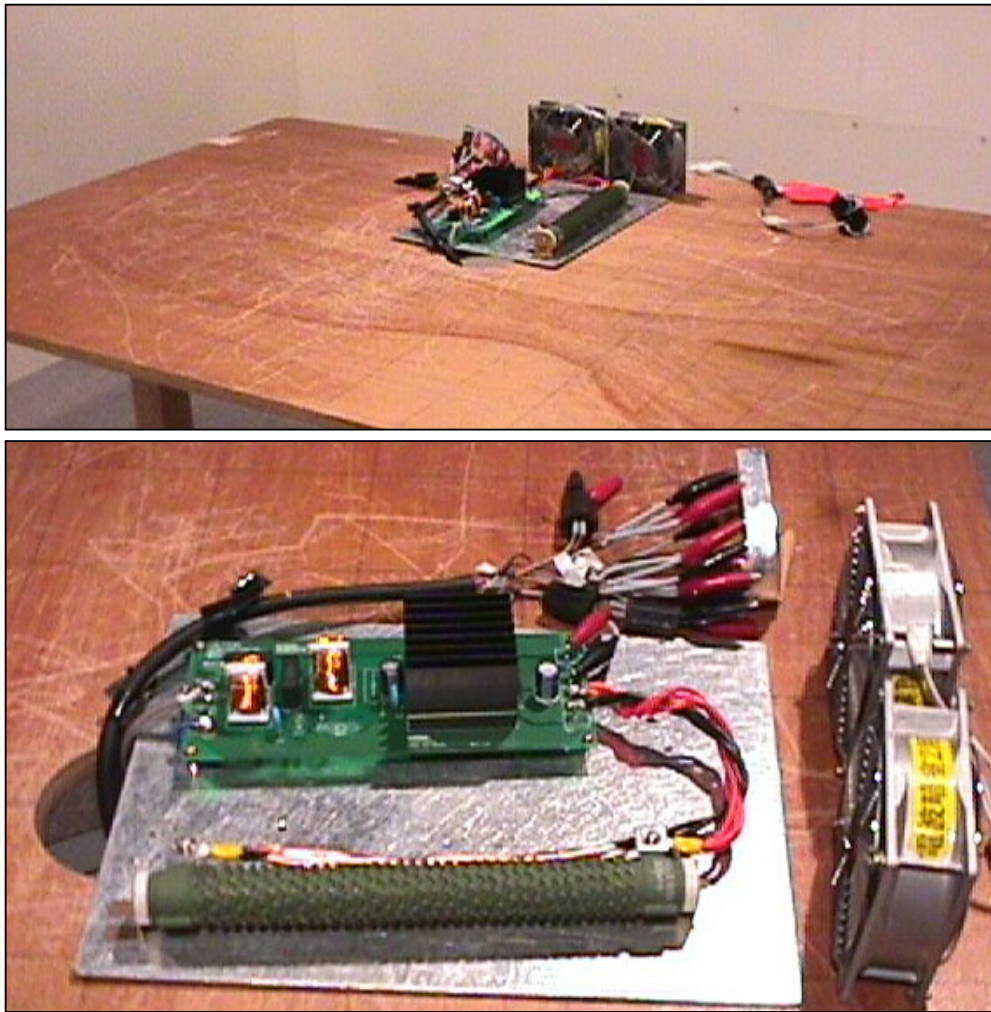
4. Result

No.	Level	Testing field strength [V/m]	Result
1	1	1	OK
2	2	3	OK
3	3	10	OK

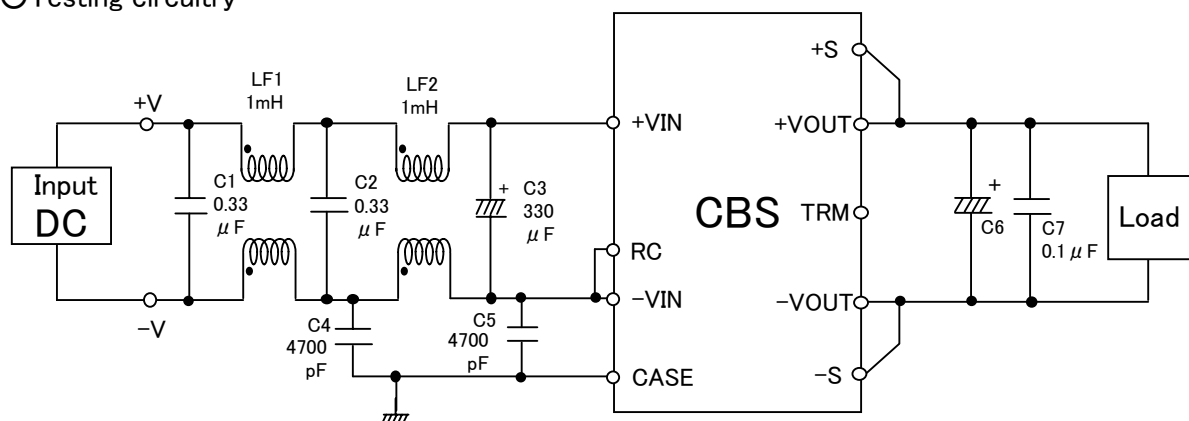
All are satisfactory to item 3: OK

Test : Radiated Susceptability
 Model Name : CBS2002405/28

○Photographs of Test Set-Up



○Testing circuitry



LF1、LF2 : SC-10-10J (TOKIN)

C1、C2 : CFJG22E334M (Nitsuko)

C3 : 50V 330 μ F PMseries (nichicon)

C4、C5 : DE1307-640E472M-KH (MURATA)

C6 : CBS2002405 10V 2200 μ F LXZseries (NIPPON CHEMI-CON)

CBS2002428 35V 470 μ F LXZseries (NIPPON CHEMI-CON)

C7 : MDD21H104M (Nitsuko)

Fig. Testing circuitry

DATA SHEET		Date	Apr.4,2002
Model	CBS2002424	Temp.	25 °C
Test	Electrical fast transient/burst immunity test 電氣的ファーストランシエントバースト試験	Humid.	40 %Rh
		Tested by	T.Oiwake

1. Method — according to EN61000-4-4 —
 - (1) Points to be applied voltage
電圧印加箇所
 - 1) Between input terminal(L) and ground plane
入力端子 (L) — グラント'プレーン間
 - 2) Between input terminal(N) and ground plane
入力端子 (N) — グラント'プレーン間
 - 3) Between FG terminal and ground plane
FG端子 — グラント'プレーン間
 - 4) Between output terminal and ground plane
出力端子 — グラント'プレーン間
 - (2) Testing shall be satisfied at the lower levels given below
印加電圧はレベル1から4まで順次実施(下表参照)
 - (3) Change the polarity (+/-) of applied voltage
印加極性 +/-の条件でそれぞれ実施
 - (4) The period of applied voltage is 1 minute
電圧印加時間は1分間

Test levels of EN61000-4-4

Level	1	2	3	4
Voltage peak [kV]	0.5	1	2	4
Repetition rate [kHz]	5	5	5	2.5

2. Conditions
 - (1) Input : DC24V
 - (2) Output : Rated output
 - (3) Ambient temp. : 25±10°C
3. Conditions of Acceptability
According to EN50082-2 (EN61000-4-4 Level 3)
EN50082-2(EN61000-4-4 レベル3)を満足すること

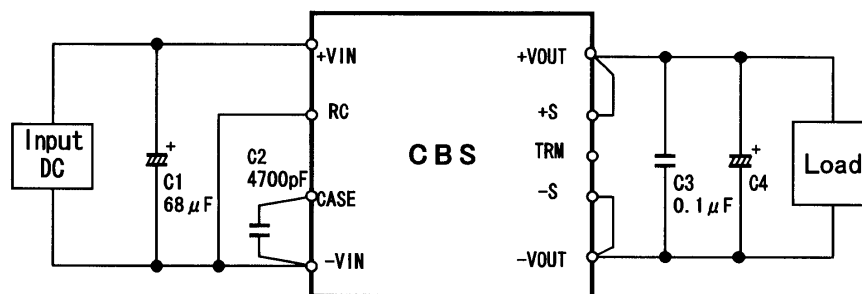
4. Result

No.	Level	Voltage [kV]	Polarity	Pin to be tested					
				+VIN	-VIN	+VOUT,+S	-VOUT,-S	CASE	RC
1	1	0.5	+	OK	OK	OK	OK	OK	OK
2			-	OK	OK	OK	OK	OK	OK
3	2	1	+	OK	OK	OK	OK	OK	OK
4			-	OK	OK	OK	OK	OK	OK
5	3	2	+	OK	OK	OK	OK	OK	OK
6			-	OK	OK	OK	OK	OK	OK
7	4	4	+	OK	OK	OK	OK	OK	OK
8			-	OK	OK	OK	OK	OK	OK

All are satisfactory to item 3: OK



5. Testing circuitry



C4 : 470 μF 35V Electrolytic capacitor

Fig. Testing circuitry

DATA SHEET		Date	2002/4/17
Model	CBS2002428	Temp.	25 °C
Test	Surge immunity test サージ・イミュニティ試験	Humid.	40 %Rh
		Tested by	T.Oiwake

1. Method — according to EN61000-4-5 —

(1) Points to be applied voltage

電圧印加箇所

— Line to line (ライン - ライン間 : ノーマル) —

1) Between input pin (+V) and input pin (-V)

入力ピン(+V) - 入力ピン(-V)

— Line to case pin (ライン - ケースピン間 : コモン) —

2) Between input pin (+V) and case pin

入力ピン(+V) - ケースピン

3) Between input pin (-V) and case pin

入力ピン(-V) - ケースピン

(2) Test at the selected levels shown below

印加電圧(レベル)は、下表に従う

(3) Change the polarity (+/-) of applied voltage

印加極性 +/- の条件でそれぞれ実施

(4) Number of tests : Six positive and six negative at selected points.

試験の回数 : それぞれの印加箇所、正負各6回試験する

(5) Repetition rate : maximum 1/min.

繰り返し速度 : 最大1回/分 (1分以上の間隔をおく)

Test levels of EN61000-4-5

Level	1	2	3	4
Test voltage [kV]	0.5	1	2	4

2. Conditions

- (1) Input : DC24V
- (2) Output : Rated output
- (3) Ambient temp. : 25±10°C
- (4) Testing circuitry : Refer to item 5

3. Conditions of Acceptability

Line to line : According to EN50082-2 (EN61000-4-5 Level 3)

ライン - ライン間 (ノーマル) : EN50082-2 (EN61000-4-5 レベル3) を満足すること

Line to earth : According to EN50082-2 (EN61000-4-5 Level 4)

ライン - ケースピン間 (コモン) : EN50082-2 (EN61000-4-5 レベル4) を満足すること

4. Result

No.	Voltage [kV]	Polarity	Line (+V) - Line (-V)
1	0.5	+	OK
2		-	OK
3	1	+	OK
4		-	OK
5	2	+	OK
6		-	OK

No.	Voltage [kV]	Polarity	Line (+V) - Case pin	Line (-V) - Case pin
1	0.5	+	OK	OK
2		-	OK	OK
3	1	+	OK	OK
4		-	OK	OK
5	2	+	OK	OK
6		-	OK	OK
7	4	+	OK	OK
8		-	OK	OK

All are satisfactory to item 3: OK

5. Testing circuitry

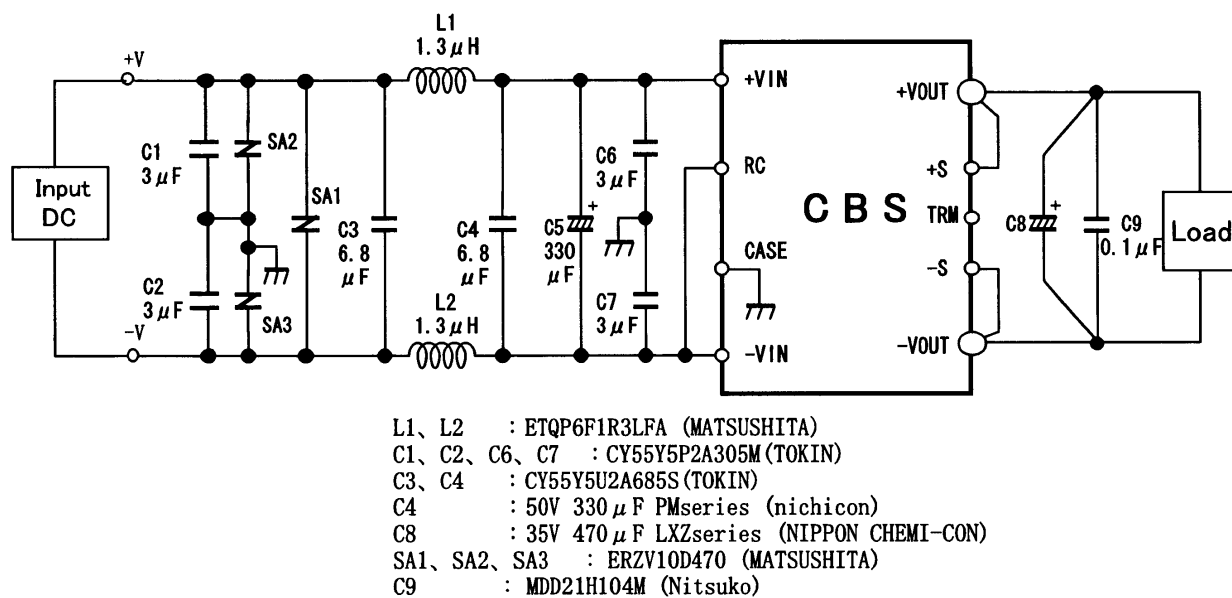


Fig. Testing circuitry

DATA SHEET		Date	2002/4/17
Model	CBS2002428	Temp.	25 °C
Test	Surge immunity test サージ・イミュニティ試験	Humid.	40 %Rh
		Tested by	T.Oiwake

1. Method — according to EN61000-4-5 —

(1) Points to be applied voltage

電圧印加箇所

— Line to line (ライン - ライン間 : ノーマル) —

1) Between input pin (+V) and input pin (-V)

入力ピン(+V) - 入力ピン(-V)

— Line to case pin (ライン - ケースピン間 : コモン) —

2) Between input pin (+V) and case pin

入力ピン(+V) - ケースピン

3) Between input pin (-V) and case pin

入力ピン(-V) - ケースピン

(2) Test at the selected levels shown below

印加電圧(レベル)は、下表に従う

(3) Change the polarity (+/-) of applied voltage

印加極性 +/- の条件でそれぞれ実施

(4) Number of tests : Six positive and six negative at selected points.

試験の回数 : それぞれの印加箇所、正負各6回試験する

(5) Repetition rate : maximum 1/min.

繰り返し速度 : 最大1回/分 (1分以上の間隔をおく)

Test levels of EN61000-4-5

Level	1	2	3	4
Test voltage [kV]	0.5	1	2	4

2. Conditions

(1) Input : DC24V

(2) Output : Rated output

(3) Ambient temp. : 25 ± 10°C

(4) Testing circuitry : Refer to item 5

3. Conditions of Acceptability

Line to line : According to EN50082-2 (EN61000-4-5 Level 3)

ライン - ライン間 (ノーマル) : EN50082-2 (EN61000-4-5 レベル3) を満足すること

Line to earth : According to EN50082-2 (EN61000-4-5 Level 4)

ライン - ケースピン間 (コモン) : EN50082-2 (EN61000-4-5 レベル4) を満足すること

4. Result

No.	Voltage [kV]	Polarity	Line (+V) - Line (-V)
1	0.5	+	OK
2		-	OK
3	1	+	OK
4		-	OK
5	2	+	OK
6		-	OK

No.	Voltage [kV]	Polarity	Line (+V) - Case pin	Line (-V) - Case pin
1	0.5	+	OK	OK
2		-	OK	OK
3	1	+	OK	OK
4		-	OK	OK
5	2	+	OK	OK
6		-	OK	OK
7	4	+	OK	OK
8		-	OK	OK

All are satisfactory to item 3: OK

[illegible]

Fig. Testing circuitry



CBS20048 EMI/EMS Test result

May 13, 2003
Design engineering dep.

Approved : *J. Yasuda*

Prepared : *T. Oiwake*

No.	Test item	Conditions	Conditions of Acceptability	Result
1	Line conduction	(1) Rated input(DC48V) (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Testing circuitry Fig.1 and Fig.3	(1)Meets the undermentioned standard. FCC Part15 classB , VCCI classB CISPR22 classB , EN55022-B	OK
2	Radiated emission	(1) Rated input(DC48V) (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Testing circuitry Fig.1 and Fig.3	(1)Meets the undermentioned standard. FCC Part15 classB , VCCI classB CISPR22 classB , EN55022-B	OK
3	Static electricity immunity test (EN61000-4-2)	(1) Rated input(DC48V) (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Contact discharge voltage 8[kV] (EN61000-4-2 Level 4) (5) Testing circuitry Fig.5	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK
4	Radiated, radio-frequency, electromagnetic field immunity test (EN61000-4-3)	(1) Rated input(DC48V) (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4)Testing field strength 10[V/m] (EN61000-4-3 Level 3) (5) Testing circuitry Fig.3	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK
5	Electrical fast transient/ burst immunity test (EN61000-4-4)	(1) Rated input(DC48V) (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Test peak voltage 4[kV] (IEC61000-4-4 Level 4) (5) Testing circuitry Fig.5	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK
6	Surge immunity test (EN61000-4-5)	(1) Rated input(DC48V) (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Test voltage Line to line 2[kV] (Level 3) Line to earth 4[kV] (Level 4) (5) Testing circuitry Fig.2 and Fig.4	(1)The power supply is not stop (2)Circuit does not malfunction. (3)No abnormality of the insulation destruction etc. (4)Parts are no damaged.	OK
7	Immunity to conducted disturbances, induced by radio-frequency fields (EN61000-4-6)	(1) Rated input (DC48V) (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Voltage level (e.m.f.) 10[V] (EN61000-4-6 Level 3) (5) Testing circuitry Fig.3	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK

○EMI/EMS testing circuitry

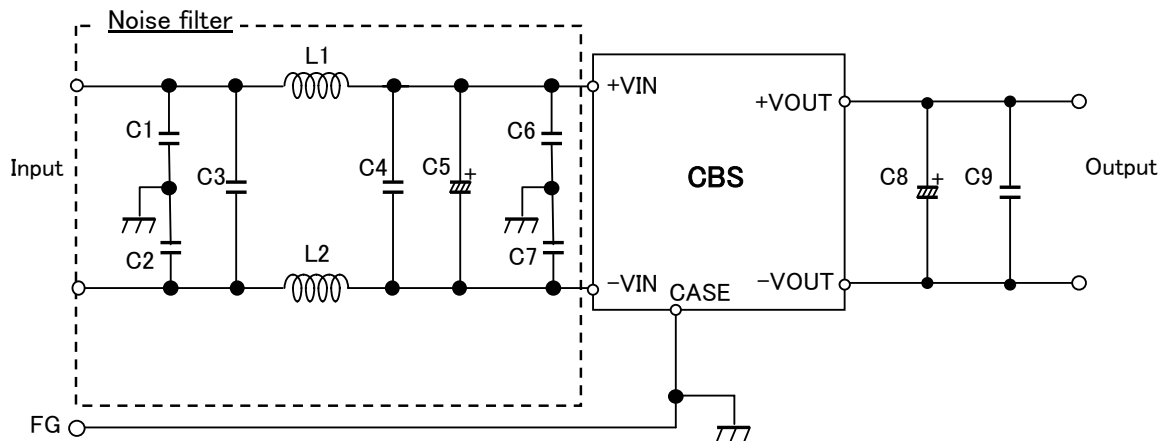


Fig.1 testing circuitry (No.1 and No.2)

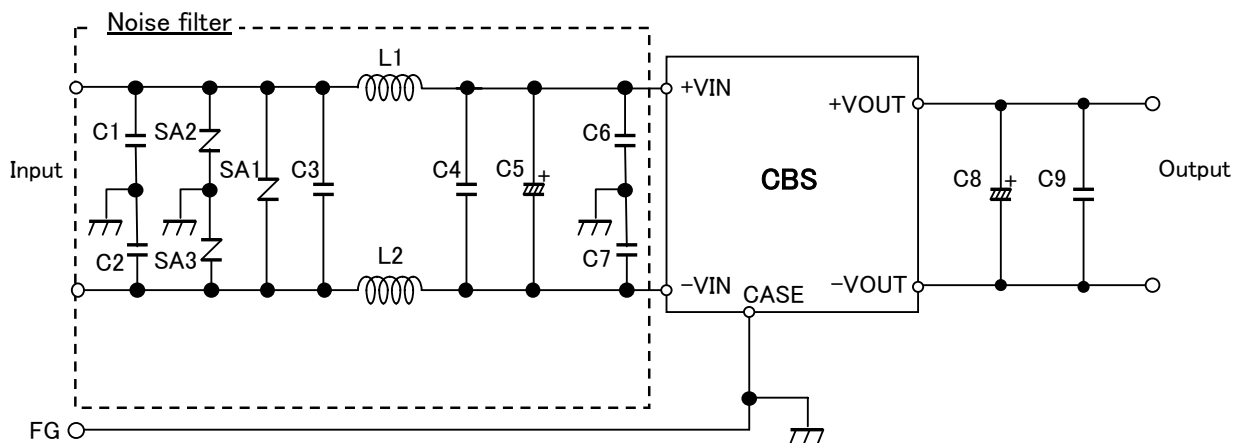


Fig.2 testing circuitry (No.6)

- | | |
|------------------------|--|
| C1, C2, C3, C4, C6, C7 | : 3 μ F 100V Ceramic capacitor |
| C5 | : 220 μ F 80V Electrolytic capacitor |
| C8 | : 2200 μ F 10V Electrolytic capacitor (CBS2004803, 05) |
| | : 1000 μ F 25V Electrolytic capacitor (CBS2004812, 15) |
| | : 470 μ F 35V Electrolytic capacitor (CBS2004824, 28) |
| | : 330 μ F 100V Electrolytic capacitor (CBS2004848) |
| C9 | : 0.1 μ F Film capacitor |
| L1, L2 | : 1.3 μ H Choke Coil |
| SA1 | : ERZV10D101 (MATSUSHITA ELECTNIC CO., LTD.) |
| SA2, SA3 | : ERZV07D820 (MATSUSHITA ELECTNIC CO., LTD.) |
| | or equivalent |

○EMI/EMS testing circuitry

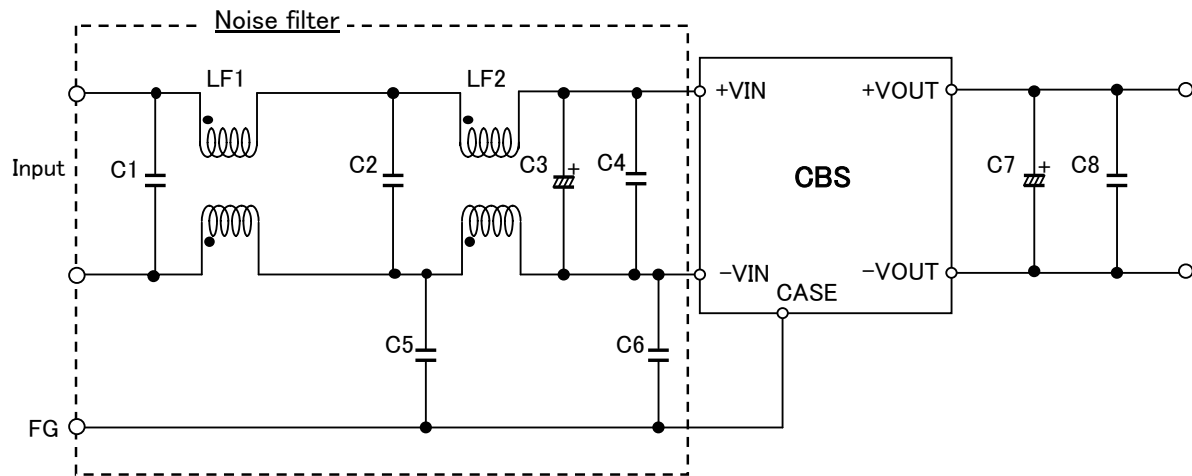


Fig.3 testing circuitry (No.1, No.2, No.4 and No.7)

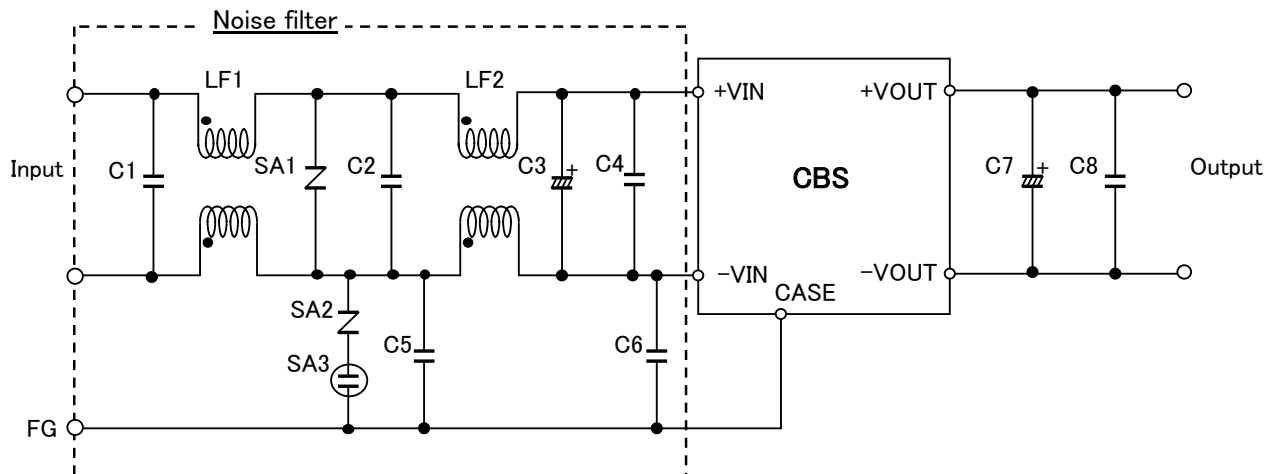


Fig.4 testing circuitry (No.6)

- C1、C2、C4 : 0.33 μ F 250V Film capacitor
- C3 : 33 μ F 100V Electrolytic capacitor
- C5、C6 : 4700pF 250V Ceramic capacitor
- C7 : 2200 μ F 10V Electrolytic capacitor (CBS2004803、05)
- : 1000 μ F 25V Electrolytic capacitor (CBS2004812、15)
- : 470 μ F 35V Electrolytic capacitor (CBS2004824、28)
- : 330 μ F 100V Electrolytic capacitor (CBS2004848)
- C8 : 0.1 μ F Film capacitor
- LF1、LF2 : 3.0mH 5A Common mode Choke Coil
- SA1、SA2 : ERZV10D101 (MATSUSHITA ELECTNIC CO., LTD.)
- SA3 : DSA-302MA (MITSUBISHI MATERIALS CORP ADVANCED PRODUCTS)
- or equivalent

C1 : 33 μ F 100V Electrolytic capacitor
C2 : 4700pF 250V Ceramic capacitor
C3 : 0.1 μ F Film capacitor
C4 : 2200 μ F 10V Electrolytic capacitor (CBS2004803、05)
: 1000 μ F 25V Electrolytic capacitor (CBS2004812、15)
: 470 μ F 35V Electrolytic capacitor (CBS2004824、28)
: 330 μ F 100V Electrolytic capacitor (CBS2004848)
or equivalent